

THS7530 High-Speed, Fully Differential, Continuously Variable Gain Amplifier

1 Features

- Low Noise: $V_n = 1.1 \text{ nV}/\sqrt{\text{Hz}}$, Noise Figure = 9 dB
- Low Distortion:
 - $HD_2 = -65 \text{ dBc}, HD_3 = -61 \text{ dBc} \text{ at } 32 \text{ MHz}$
 - $IMD_3 = -62 \text{ dBc}$, $OIP_3 = 21 \text{ dBm}$ at 70 MHz
- 300-MHz Bandwidth
- Continuously Variable Gain Range: 11.6 dB to 46.5 dB
- Gain Slope: 38.8 dB/V
- Fully Differential Input and Output
- Output Common-Mode Voltage Control
- Output Voltage Limiting

2 Applications

- Time Gain Amplifiers in Ultra Sound, Sonar, and Radar
- Automatic Gain Control in Communication and Video
- System Gain Calibration in Communications
- Variable Gain in Instrumentation

3 Description

The THS7530 device is fabricated using Texas Instruments' state-of-the-art BiCom III SiGe complementary bipolar process. The THS7530 device is a DC-coupled, wide bandwidth amplifier with voltage-controlled gain. The amplifier has highimpedance differential inputs and low-impedance differential outputs with high-bandwidth gain control, output common-mode control, and output voltage clamping.

Signal-channel performance is exceptional with 300-MHz bandwidth, and third harmonic distortion of – 61 dBc at 32 MHz with $1-V_{PP}$ output into 400 Ω .

Gain control is linear in dB with 0 V to 0.9 V varying the gain from 11.6 dB to 46.5 dB with 38.8-dB/V gain slope.

Output voltage limiting is provided to limit the output voltage swing and to prevent saturating following stages.

The device is characterized for operation over the industrial temperature range, -40° C to $+85^{\circ}$ C.

Device Information (1)

PART NUMBER	PACKAGE	BODY SIZE (NOM)			
THS7530	HTSSOP (14)	5.00 mm × 4.40 mm			

(1) For all available packages, see the orderable addendum at the end of the data sheet.



Typical Application Circuit

An IMPORTANT NOTICE at the end of this data sheet addresses availability, warranty, changes, use in safety-critical applications, intellectual property matters and other important disclaimers. PRODUCTION DATA.



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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	hanges from Revision D (July 2015) to Revision E (August 2020)	Page
•	Updated the numbering format for tables, figures, and cross-references throughout the document	1
С	hanges from Revision C (February 2010) to Revision D (July 2015)	Page
•	Added ESD Ratings table, Feature Description section, Device Functional Modes, Application and Implementation section, Power Supply Recommendations section, Layout section, Device and Documentation Support section, and Mechanical, Packaging, and Orderable Information section	1
c	hanges from Revision B (February 2006) to Revision C (February 2010)	Page
<u>с</u>	hanges from Revision B (February 2006) to Revision C (February 2010) Corrected polarity indication on input and output in front-page figure	
<u>c</u> •		1
•	Corrected polarity indication on input and output in front-page figure	
•	Corrected polarity indication on input and output in front-page figure Deleted <i>lead temperature</i> specification from Absolute Maximum Ratings table	



5 Pin Configuration and Functions





Pin Functions

P	PIN		PIN		DESCRIPTION
NAME	NO.	I/O	DESCRIPTION		
NC	1		No internal connection		
	2				
PD	7	—	Power down, \overline{PD} = logic low puts the device into low power mode; \overline{PD} = logic high or open for normal operation		
V _{CL-}	13	I	Output negative clamp voltage input		
V _{CL+}	14	I	Output positive clamp voltage input		
V _{G-}	6	I	Gain setting negative input		
V _{G+}	5	I	Gain setting positive input		
V _{IN-}	4	I	Inverting amplifier input		
V _{IN+}	3	I	Noninverting amplifier input		
V _{OCM}	12	I	Output common-mode voltage input		
V _{OUT-}	11	0	Inverted amplifier output		
V _{OUT+}	10	0	Noninverted amplifier output		
V _{S-}	8	I	Negative amplifier power-supply input		
V _{S+}	9	I	Positive amplifier power-supply input		



6 Specifications

6.1 Absolute Maximum Ratings

Over operating free-air temperature range, unless otherwise noted.⁽¹⁾

		MIN	MAX	UNIT
$V_{S+} - V_{S-}$	Supply voltage		5.5	V
VI	Input voltage		±V _S	V
I _O	Output current		65	mA
V _{ID}	Differential input voltage		±4	V
	Continuous power dissipation		See Section 6.4	
-	Maximum junction temperature		150	°C
IJ	Maximum junction temperature for long term stability ⁽²⁾		125	°C
T _{stg}	Storage temperature	-65	150	°C

(1) Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The maximum junction temperature for continuous operation is limited by package constraints. Operation above this temperature may result in reduced reliability and/or lifetime of the device.

6.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±3000	
V _(ESD)	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1500	V
		Machine model (MM)	±200	

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

			MIN	NOM	MAX	UNIT
$[V_{S-} \text{ to } V_{S+}]$	Supply voltage		4.5	5	5.5	V
	Input common mode voltage	$[V_{S-} \text{ to } V_{S+}] = 5 \text{ V}$		2.5		V
	Output common mode voltage	$[V_{S-} \text{ to } V_{S+}] = 5 \text{ V}$		2.5		V
T _A	Operating free-air temperature		-40		85	°C

6.4 Thermal Information

		THS7530	
	THERMAL METRIC ⁽¹⁾	PWP (HTSSOP)	UNIT
		14 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	50.4	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	34.9	°C/W
R _{θJB}	Junction-to-board thermal resistance	29	°C/W
Ψ _{JT}	Junction-to-top characterization parameter	1.6	°C/W
Ψ _{ЈВ}	Junction-to-board characterization parameter	28.7	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	3.2	°C/W

(1) For more information about traditional and new thermal metrics, see the *Semiconductor and IC Package Thermal Metrics* application report, SPRA953.



6.5 Electrical Characteristics: Main Amplifier

 $V_{S+} = 5 V$, $V_{S-} = 0 V$, $V_{OCM} = 2.5 V$, $V_{ICM} = 2.5 V$, $V_{G-} = 0 V$, $V_{G+} = 1 V$ (maximum gain), $T_A = 25^{\circ}C$, AC performance measured using the AC test circuit shown in Figure 7-1 (unless otherwise noted). DC performance is measured using the DC test circuit shown in Figure 7-2 (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
AC PERFORMANCE					
Small-signal bandwidth	All gains, P _{IN} = –45 dBm		300		MHz
Slew rate ⁽¹⁾	1-V _{PP} Step, 25% to 75%, minimum gain		1250		V/µs
Settling time to 1% ⁽¹⁾	1-V _{PP} Step, minimum gain		11		ns
Harmonic distortion, 2nd harmonic	f = 32 MHz, $V_{O(PP)}$ = 1 V, $R_{L(diff)}$ = 400 Ω		-65		dBc
Harmonic distortion, 3rd harmonic	f = 32 MHz, $V_{O(PP)}$ = 1 V, $R_{L(diff)}$ = 400 Ω		-61		dBc
Third-order intermodulation distortion	P_{O} = -10 dBm each tone, f _C = 70 MHz, 200-kHz tone spacing		-62		dBc
Third-order output intercept point	f _C = 70 MHz, 200-kHz tone spacing		21		dBm
Noise figure (with input termination)	Source impedance: 50 Ω		9		dB
Total input voltage noise	f > 100 kHz		1.1		nV/√ Hz
DC PERFORMANCE—INPUTS					
	T _A = 25°C		20	39	
Input bias current	$T_A = -40^{\circ}C$ to +85°C			40	μA
Input bias current offset			<150		pА
	Minimum gain, T _A = 25°C		1.5	1.6	
Minimum input voltage	Minimum gain, $T_A = -40^{\circ}C$ to +85°C			1.7	V
	Minimum gain, T _A = 25°C	3.35	3.5		
Maximum input voltage	Minimum gain, $T_A = -40^{\circ}$ C to +85°C	3.2		V	V
	T _A = 25°C	56	114		
Common-mode rejection ratio	$T_A = -40^{\circ}C$ to +85°C	44			dB
Differential input impedance			8.5 3		kΩ pF
DC PERFORMANCE—OUTPUTS					
	All gains, T _A = 25°C		±100	±340	
Output offset voltage	All gains, $T_A = -40^{\circ}$ C to +85°C			±480	mV
	$T_A = 25^{\circ}C$	3.275	3.5		
Maximum output voltage high	$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$	3.25			V
	$T_A = 25^{\circ}C$		1.5	1.7	
Minimum output voltage low	$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$			1.8	V
	$T_A = 25^{\circ}C$	±16	±37		
Output current	$T_{A} = -40^{\circ}C \text{ to } +85^{\circ}C$	±16			mA
Output impedance			15		Ω
OUTPUT COMMON-MODE VOLTAGE C	ONTROL				
Small-signal bandwidth			32		MHz
Gain			1		V/V
	T _A = 25°C		4.5	12	
Common-mode offset voltage	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$		1.0	13.8	mV
Minimum input voltage			1.75		V
Maximum input voltage			3.25		V
Input impedance			25 1		kΩ pF
Default voltage, with no connect			2.5		V
Input bias current			<1		μA
GAIN CONTROL			11		μ, ,
Gain control differential voltage range	V _{G*}		0 to 1		V
			-0.6 to 0.8		V V
Minus gain control voltage	$V_{G-} - V_{S-}$				
Minimum gain	V _{G+} = 0 V		11.6		dB

6.5 Electrical Characteristics: Main Amplifier (continued)

 $V_{S+} = 5 V$, $V_{S-} = 0 V$, $V_{OCM} = 2.5 V$, $V_{ICM} = 2.5 V$, $V_{G-} = 0 V$, $V_{G+} = 1 V$ (maximum gain), $T_A = 25^{\circ}C$, AC performance measured using the AC test circuit shown in Figure 7-1 (unless otherwise noted). DC performance is measured using the DC test circuit shown in Figure 7-2 (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	ТҮР	MAX	UNIT
Maximum gain	V _{G+} = 0.9 V		46.5		dB
Gain slope	V _{G+} = 0 V to 0.9 V		38.8		dB/V
Gain slope variation	V _{G+} = 0 V to 0.9 V		±1.5		dB/V
0.	V _{G+} = 0 V to 0.15 V		±4		
Gain error	V _{G+} = 0.15 V to 0.9 V		±2.25		dB
Gain control input bias current			<1		μA
Gain control input resistance			40		kΩ
Gain control bandwidth	Small signal –3 dB		15		MHz
VOLTAGE CLAMPING					
Output voltages (V _{OUT+}) relative to clamp	Device In voltage limiting mode, $T_A = 25^{\circ}C$		±25	±38	
voltages (V _{CL±})	Device In voltage limiting mode, $T_A = -40^{\circ}C$ to +85°C			±60	mV
Clamp voltage (V _{CL±}) input resistance	Device in voltage limiting mode		3.3		kΩ
Clamp voltage (V _{CL±}) limits		Vs	to V _{S+}		V
POWER SUPPLY					
	T _A = 25°C		5	5.5	
Specified operating voltage	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$			5.5	V
	T _A = 25°C		40	48	
Maximum quiescent current	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$			49	mA
	$T_{A} = 25^{\circ}C$ 70	70	77		
Power supply rejection (±PSRR)	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$	45			dB
POWER DOWN					
	TTL low = shut down, T _A = 25°C		1.4		
Enable voltage threshold	TTL low = shut down, $T_A = -40^{\circ}C$ to +85°C	1			V
	TTL high = normal operation, $T_A = 25^{\circ}C$		1.4		
Disable voltage threshold	TTL high = normal operation, $T_A = -40^{\circ}C$ to +85°C			1.65	V
	T _A = 25°C		0.35	0.4	
Power-down quiescent current	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$			0.45	mA
	T _A = 25°C		±9	±16	
nput current high	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$			±19	μA
	T _A = 25°C		±109	±116	
nput current low	$T_A = -40^{\circ}C \text{ to } +85^{\circ}C$			±119	μA
nput impedance			50 1		kΩ pF
Furnon time delay	Measured to 50% quiescent current		820		ns
Turnoff time delay	Measured to 50% quiescent current		500		ns
Forward isolation in power down			80		dB
Input resistance in power down			> 1		MΩ
Output resistance in power down			16		kΩ

(1) Slew rate and settling time measured at amplifier output.



6.6 Package Thermal Data

PACKAGE	РСВ	T _A = 25°C POWER RATING ⁽¹⁾
PWP (14-pin) ⁽²⁾	See Section 11.	3 W

(1) This data was taken using 2 oz trace and copper pad that is soldered directly to a 3 in × 3 in PCB.

(2) The THS7530 incorporates a PowerPAD on the underside of the chip. The PowerPAD acts as a heatsink and must be connected to a thermally dissipative plane for proper power dissipation. Failure to do so may result in exceeding the maximum junction temperature which could permanently damage the device. See TI technical briefs SLMA002 and SLMA004 for more information about using the PowerPAD thermally enhanced package.

6.7 Typical Characteristics

Measured using the AC test circuit shown in Figure 7-1 (unless otherwise noted).

		FIGURE
Voltage Gain to Load	vs Frequency (Input at 45 dBm)	Figure 6-1
Gain and Gain Error	vs V _{G+}	Figure 6-2
Noise Figure	vs Frequency	Figure 6-3
Output Intercept Point	vs Frequency	Figure 6-4
1-dB Compression Point	vs Frequency	Figure 6-5
Total Input Voltage Noise	vs Frequency	Figure 6-6
Intermodulation Distortion	vs Frequency	Figure 6-7
Harmonic Distortion	vs Frequency	Figure 6-8
S-Parameters	vs Frequency	Figure 9-7
Differential Input Impedance of Main Amplifier	vs Frequency	Figure 9-8
Differential Output Impedance of Main Amplifier	vs Frequency	Figure 6-9
V _{G+} Input Impedance	vs Frequency	Figure 6-10
V _{OCM} Input Impedance	vs Frequency	Figure 6-11
Common-Mode Rejection Ratio	vs Frequency	Figure 6-12
Step Response: 2 V _{PP}	vs Time	Figure 6-13
Step Response: Rising Edge	vs Time	Figure 6-14
Step Response: Falling Edge	vs Time	Figure 6-15

Table 6-1. Table Of Graphs

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0.2

0

-0.2

-0.4

-0.6

-0.8

1000

Gain Error

800

600

400

 $$v_{\rm G+}$ Voltage (mV)$ Figure 6-2. Gain and Gain Error vs <math display="inline">V_{G+}$

Gain Error (dB)



Figure 6-1. Voltage Gain to Load vs Frequency



45

40

35

30

କୁ 25

.ie 20

15

10

5

0

0

Gain

Gain Error

200

Gain





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7 Parameter Measurement Information

7.1 Test Circuits



Figure 7-1. AC Test Circuit



Figure 7-2. DC Test Circuit



8 Detailed Description

8.1 Overview

The THS7530 device is a fully-differential amplifier with 300-MHz bandwidth and with continually-variable gain from 11.6 dB to 46.5 dB. This amplifier together with an automatic gain control (AGC) circuit will precisely established a desired amplitude at its output.

The input architecture is a modified Gilbert cell. The output from the Gilbert cell is converted to a voltage and buffered to the output as a fully-differential signal. A summing node between the outputs is used to compare the output common-mode voltage to the V_{OCM} input. The V_{OCM} error amplifier then servos the output common-mode voltage to the V_{OCM} input. Left unterminated, V_{OCM} is set to midsupply by internal resistors.

The gain control input is conditioned to give linear-in-dB gain control (block H). The gain control input is a differential signal from 0 V to 0.9 V which varies the gain from 11.6 dB to 46.5 dB.

 V_{CL+} and V_{CL-} provide inputs that limit the output voltage swing of the amplifier.

8.2 Functional Block Diagram



8.3 Feature Description

The main features of the THS7530 device are continually-variable gain control, common-mode voltage control, output voltage clamps, and power-down mode.

8.3.1 Continually-Variable Gain Control

The amplifier gain in dB is a linear function of the gain control voltage, which has a range of 0 V to 0.9 V. The slope of the gain control input is 38.8 dB/V with a gain range of 11.6 dB to 46.5 dB, which is 3.8 to 211.3 V/V, respectively. The bandwidth of the gain control is 15 MHz, typically.

The gain control is a differential input to reduce noise due to ground bounce, coupling, and so forth. The negative gain-control input V_{G-} can be below the negative supply by as much as 600 mV.

8.3.2 Common-Mode Voltage Control

The common-mode voltage control sets the common-mode voltage of the differential output. The gain of the control voltage is 1 V/V with a range of 1.75 V to 3.25 V above the negative supply. If unconnected, the common-mode voltage control is at mid-supply, typically 2.5 V above the negative supply. The bandwidth of the common-mode voltage control is an impressive 32 MHz.



8.3.3 Output Voltage Clamps

Separate inputs, V_{CL-} and V_{CL+} , establish the minimum and maximum output voltages, respectively. The typical error of the output voltage compared to the clamp voltage is only 25 mV. This feature can be used to avoid saturating the inputs of a receiving device, thereby precluding long recovery times in the signal path.

8.3.4 Power-Down Mode

To minimize power consumption when idle, the THS7530 device has an active-low power-down control that reduces the quiescent current from 40 mA to 350 µA. The turnon delay is only 820 ns.

When in power-down mode, the THS7530 device has a 80-dB forward isolation to allow other devices to drive the same signal path with minimal interference from the idle THS7530 device.

8.4 Device Functional Modes

The THS7530 device has two functional modes: full-power mode and power-down mode. The power-down mode reduces the quiescent current of the device to 350 µA from a typical value of 40 mA.

With a turnon time of only 820 ns and a turnoff time of 500 ns, the power-down mode can be used to greatly reduce the average power consumption of the device without sacrificing system performance.



9 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The THS7530 device is designed to work in a wide variety of applications requiring continuously variable gain and a fully-differential signal path. The common-mode voltage control and the output voltage clamps enable the THS7530 device to drive a diverse array of receiving circuits.



Figure 9-1. EVM Schematic: Designed for Use With Typical 50-Ω RF Test Equipment



Figure 9-2. AC-Coupled Single-Ended Input With AC-Coupled Differential Output









Figure 9-4. DC-Coupled Single-Ended Input With DC-Coupled Differential Output



Figure 9-5. DC-Coupled Differential Input With DC-Coupled Differential Output



9.2 Typical Application



Figure 9-6. Typical Application Circuit

9.2.1 Design Requirements

A typical application circuit is shown in *Figure 9-6*. Two noteworthy aspects of this circuit are the customer's automatic gain control (AGC) circuit and the THS7530 input bias circuit.

The proper design of the AGC circuit is essential for the THS7530 device to operate properly in the customer's application. The method of detecting the amplitude of the differential output of the THS7530 device and creating the gain-control voltage, V_{G+} , from the detected amplitude and the reference amplitude, V_{ref} , are application-specific and beyond the scope of this document. The bandwidth of the amplitude of the THS7530 amplitude control is 15 MHz, which allows for rapid corrections of amplitude errors but which also allows noise from DC to 15 MHz to create an amplitude error. The trade-off between rapid amplitude correction and amplitude modulation due to noise is an important design consideration.

The input bias currents of the differential inputs of the THS7530 device are typically 20 μ A. When the differential inputs are AC-coupled, the bias currents must be supplied as shown in *Figure 9-6*. In this circuit, the DC bias voltage is mid-supply and the AC differential input impedance is 50 Ω . The 0.1- μ F capacitor between the two 24.9- Ω resistors creates an AC ground for the driving circuit.

9.2.2 Detailed Design Procedure

The THS7530 device is designed for nominal 5-V power supply from V_{S+} to V_{S-}.

The amplifier has fully differential inputs, V_{IN+} and V_{IN-} , and fully differential outputs, V_{OUT+} and V_{OUT-} The inputs are high impedance and outputs are low impedance. External resistors are recommended for impedance matching and termination purposes.

The inputs and outputs can be DC-coupled, but for best performance, the input and output common-mode voltage should be maintained at the midpoint between the two supply pins. The output common-mode voltage is controlled by the voltage applied to V_{OCM} . Left unterminated, V_{OCM} is set to midsupply by internal resistors. A 0.1-µF bypass capacitor should be placed between V_{OCM} and ground to reduce common-mode noise. The input common-mode voltage defaults to midrail when left unconnected. For voltages other than midrail, V_{OCM} must be biased by external means. V_{IN+} and V_{IN-} both require a nominal 30-µA bias current for proper operation. Therefore, ensure equal input impedance at each input to avoid generating an offset voltage that varies with gain.

Voltage applied from V_G to V_G to V_G controls the gain of the part with 38.8-dB/V gain slope. The input can be differential or single ended. V_G must be maintained within –0.6 V and 0.8 V of V_S for proper operation. The negative gain input should typically be tied directly to the negative power supply.



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 V_{CL+} and V_{CL-} are inputs that limit the output voltage swing of the amplifier. The voltages applied set an absolute limit on the voltages at the output. Input voltages at V_{CL+} and V_{CL-} clamp the output, ensuring that neither output exceeds those values.

The power-down input is a TTL compatible input, referenced to the negative supply voltage. A logic low puts the THS7530 device in power-saving mode. In power-down mode the part consumes less than 1-mA current, the output goes high impedance, and a high amount of isolation is maintained between the input and output.

Power-supply bypass capacitors are required for proper operation. A 6.8-µF tantalum bulk capacitor is recommended if the amplifier is located far from the power supply and may be shared among other devices. A ceramic 0.1-µF capacitor is recommended within 0.1-in of the device power pin. The ceramic capacitors should be located on the same layer as the amplifier to eliminate the use of vias between the capacitors and the power pin.

ITEM NO.	DESCRIPTION	SIZE	REFERENCE DESIGNATOR	QTY	PART NUMBER
1	Bead, ferrite, 3 A, 80 Ω	1206	FB1	1	(Steward) HI1206N800R-00
2	Capacitor, tantalum, 6.8 mF, 35 V, 10%	D	C2	1	(AVX) TAJD685K035R
3	Capacitor, ceramic, 0.1 mF, X7R, 16V	508	C1	1	(AVX) 0508YC104KAT2A
5	Capacitor, ceramic, 0.1 mF, X7R, 50 V	805	C3, C7, C12, C13, C14, C15, C16, C17	8	(AVX) 08055C104KAT2A
6	Diode, Schottky, 20 V, 0.5 A	SOD-123	D1	1	(Diodes Inc.) B0520LW–7
7	Resistor, 10 Ω, 1/8 W, 1%	805	R24, R25, R26	3	(PHYCOMP) 9C08052A10R0FKHFT
8	Resistor, 24.9 Ω, 1/8 W, 1%	805	R9, R15	2	(PHYCOMP) 9C08052A24R9FKHFT
9	Resistor, 1 kΩ, 1.8W, 1%	805	R7, R12	2	(PHYCOMP) 9C08052A1001FKHFT
10	Resistor, 3.92 kΩ , 1/8 W, 1%	805	R1	1	(PHYCOMP) 9C08052A3921FKHFT
11	Resistor, 0 Ω, 1/4 W	1206	C4, C5	2	(PHYCOMP) 9C12063A0R00JLHFT
12	Resistor, 49.9 Ω, 1/4 W, 1%	1206	R4	1	(PHYCOMP) 9C12063A49R9FKRFT
13	Pot., ceramic, 1/4 inch square, 1 k Ω		R2	1	(Bourns) 3362P–1–102
14	Pot., ceramic, 1/4 inch square, 10 k Ω		R21, R22, R23	3	(Bourns) 3362P–1–103
15	IC, TLV2371	SOT-23	U2, U3, U4	3	(TI) TLV2371IDBVT
16	Transformer, 1:1	CD542	T1, T2	2	(Mini-Circuits) ADT1-1WT
17	Connector, edge, SMA PCB Jack		J3, J4	2	(Johnson) 142–0701–801
18	Jack, banana receptacle, 0.25-in diameter hole		J1, J2	2	(HH Smith) 101
19	Header, 0.1-in Ctrs, 0.025-in square pins	2 POS.	JP1	1	(Sullins) PZC36SAAN
20	Shunts		JP1	1	(Sullins) SSC02SYAN
21	Test point, black		TP2, TP3, TP4	3	(Keystone) 5001
22	Test points, red		TP1, TP8, TP9, TP10	4	(Keystone) 5000
23	Standoff, 4–40 Hex, 0.625-in Length			4	(Keystone) 1804
24	Screw, Phillips, 4–40, .250-in			4	SHR-0440-016-SN
25	IC, THS7530		U1	1	(TI) THS7530PWP
26	Board, printed circuit			1	(TI) EDGE # 6441987

Table 9-1. THS7530EVM Bill of Materials



9.2.3 Application Curves



Figure 9-7 and Figure 9-8 highlight the input characteristics of the THS7530 device that should be used to design the circuit driving the THS7530 device.

10 Power Supply Recommendations

The THS7530 device is principally intended to operate with a nominal single-supply voltage of 5 V. Supply voltage tolerances of $\pm 10\%$ are supported. The absolute maximum supply is 5.5 V.

Supply decoupling is required, as described in Section 9.

Split (or bipolar) supplies can be used with the THS7530 device, as long as the total value across the device remains less than 5.5 V (absolute maximum).



11 Layout

11.1 Layout Guidelines

The THS7530 device is available in a thermally-enhanced PowerPAD[™] package. Figure 11-1 shows the recommended number of vias and thermal land size recommended for best performance. Thermal vias connect the thermal land to internal or external copper planes and should have a drill diameter sufficiently small so that the via hole is effectively plugged when the barrel of the via is plated with copper. This plug is needed to prevent wicking the solder away from the interface between the package body and the thermal land on the surface of the board during solder reflow. The experiments conducted jointly with Solectron Texas indicate that a via drill diameter of 0.33 mm (13 mils, or .013 in) or smaller works well when 1-ounce copper is plated at the surface of the board and simultaneously plating the barrel of the via. If the thermal vias are not plugged when the copper plating is performed, then a solder mask material should be used to cap the vias with a dimension equal to the via diameter + 0.1 mm minimum. This prevents the solder from being wicked through the thermal via and potentially creating a solder void in the region between the package bottom and the thermal land on the surface of the PCB.



Figure 11-1. Recommended Thermal Land Size and Thermal Via Patterns (Dimensions in mm)

See TI's Technical Brief titled, *PowerPAD™ Thermally Enhanced Package* (SLMA002) for a detailed discussion of the PowerPAD™ package, its dimensions, and recommended use.







Figure 11-2. EVM Schematic



11.2 Layout Examples



Figure 11-3. Layout Diagram (Top)



Figure 11-4. Layout Diagram (Ground)





Figure 11-5. Layout Diagram (Power)



Figure 11-6. Layout Diagram (Bottom)



12 Device and Documentation Support

12.1 Device Support

12.1.1 Third-Party Products Disclaimer

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12.1.2 Development Support

For the THS7530 PSpice Model, see SLOJ139.

For the THS7530 TINA-TI Spice Model, see SLAM020.

For the THS7530 TINA-TI Reference Design, see SLAC091.

12.2 Documentation Support

12.2.1 Related Documentation

For related documentation, see the following:

- THS7530 EVM Users Guide, SLOU161
- Noise Analysis for High-Speed Op Amps, SBOA066
- TI's Analog Signal Chain Guide, SLYB174
- PowerPAD[™] Thermally Enhanced Package, SLMA002
- PowerPAD[™] Made Easy, SLMA004

12.3 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

12.4 Trademarks

PowerPAD[™] is a trademark of Texas Instruments.

TI E2E[™] is a trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

12.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.6 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



10-Dec-2020

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
THS7530PWP	ACTIVE	HTSSOP	PWP	14	90	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	THS7530	Samples
THS7530PWPR	ACTIVE	HTSSOP	PWP	14	2000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	THS7530	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <= 1000ppm threshold. Antimony trioxide based flame retardants must also meet the <= 1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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www.ti.com

PACKAGE OPTION ADDENDUM

10-Dec-2020

OTHER QUALIFIED VERSIONS OF THS7530 :

• Automotive: THS7530-Q1

NOTE: Qualified Version Definitions:

• Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

PACKAGE MATERIALS INFORMATION

Texas Instruments

www.ti.com

TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
THS7530PWPR	HTSSOP	PWP	14	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1



www.ti.com

PACKAGE MATERIALS INFORMATION

5-Jan-2022



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
THS7530PWPR	HTSSOP	PWP	14	2000	350.0	350.0	43.0



www.ti.com

5-Jan-2022

TUBE



*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	Τ (μm)	B (mm)
THS7530PWP	PWP	HTSSOP	14	90	530	10.2	3600	3.5

PWP 14

GENERIC PACKAGE VIEW

PowerPAD TSSOP - 1.2 mm max height

4.4 x 5.0, 0.65 mm pitch

PLASTIC SMALL OUTLINE

This image is a representation of the package family, actual package may vary. Refer to the product data sheet for package details.





PWP (R-PDSO-G14)

PowerPAD[™] PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in millimeters.

- This drawing is subject to change without notice. Β.
- C. Body dimensions do not include mold flash or protrusions. Mold flash and protrusion shall not exceed 0.15 per side.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad
- Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 for information regarding recommended board layout. This document is available at www.ti.com http://www.ti.com.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.

E. Falls within JEDEC MO-153

PowerPAD is a trademark of Texas Instruments.



PWP (R-PDSO-G14) PowerPAD[™] SMALL PLASTIC OUTLINE

THERMAL INFORMATION

This PowerPAD[™] package incorporates an exposed thermal pad that is designed to be attached to a printed circuit board (PCB). The thermal pad must be soldered directly to the PCB. After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For additional information on the PowerPAD package and how to take advantage of its heat dissipating abilities, refer to Technical Brief, PowerPAD Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 and Application Brief, PowerPAD Made Easy, Texas Instruments Literature No. SLMA004. Both documents are available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



PowerPAD is a trademark of Texas Instruments





NOTES:

A.

- This drawing is subject to change without notice. Β.
- Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad. C.
- This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad D. Thermally Enhanced Package, Texas Instruments Literature No. SLMA002, SLMA004, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.
- F.



PWP (R-PDSO-G14)

PowerPAD[™] PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in millimeters.

- This drawing is subject to change without notice. Β.
- C. Body dimensions do not include mold flash or protrusions. Mold flash and protrusion shall not exceed 0.15 per side.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad
- Thermally Enhanced Package, Texas Instruments Literature No. SLMA002 for information regarding recommended board layout. This document is available at www.ti.com http://www.ti.com.
- E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.

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PWP (R-PDSO-G14) PowerPAD[™] SMALL PLASTIC OUTLINE

THERMAL INFORMATION

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The exposed thermal pad dimensions for this package are shown in the following illustration.



A. Exposed tie strap features may not be present.

PowerPAD is a trademark of Texas Instruments





NOTES:

A.

- This drawing is subject to change without notice. Β.
- Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad. C.
- This package is designed to be soldered to a thermal pad on the board. Refer to Technical Brief, PowerPad D. Thermally Enhanced Package, Texas Instruments Literature No. SLMA002, SLMA004, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <http://www.ti.com>. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.
- F.



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